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Hayes
PATENT
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re issuance application of:

Tomomi Momohara

Serial No: Not Assigned

Filed: Herewith

Patent No.: 5,818,249

Issued: October 6, 1998

For: PROBE CARD HAVING GROUPS OF PROBE
NEEDLES IN A PROBING TEST APPARATUS
FOR TESTING SEMICONDUCTOR
INTEGRATED CIRCUITS

Art Unit: Not Assigned

Examiner: Not Assigned

KOT
10/3/02

PRELIMINARY AMENDMENT

BOX REISSUE

Assistant Commissioner for Patents

Washington, D.C. 20231

Dear Sir:

Before examining the present application, please enter the following amendments:

IN THE SPECIFICATION:

Please amend the specification as indicated:

In the paragraph beginning at line 41 of column 1, enter the indicated amendment:

A1
The integration density of semiconductor integrated circuits, particularly semiconductor memories, is still increasing. The time for testing one chip inevitably increases even if the probe card 5 (FIG. 1) is used. In order to shorten the time, it is necessary to provide more groups of [prove] probe needles for each column so that the card 5 may test more chips at the same time.

In the paragraph beginning at line 57 of column 1, enter the indicated amendment:

A2
When the probe card 5' was used to accomplish a probing test, however, more chips were likely [found] to be found defective than in the case where the probe card 5